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Substitute for form 144	-5/F1 O		Application Number	10/654,790		
INFORMAT	TION DIS	CLOSURE	Filing Date	9/4/03	 	
STATEME	NT BY A	PPLICANT	First Named Inventor	Pan		
<i>atas as m</i>			Art Unit	2818		
(Use as many sheets as necessary)			Examiner Name	M. Tran		
Sheet 1	of	5	Attorney Docket Number			

		NON PATENT LITERATURE DOCUMENTS	
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	1	J.L. PAN, J.E. McMANUS, L. GROBER and J.M. WOODWALL, Gallium-arsenide deep-level pin tunnel diode with very negative conductance, Electronics Letters, Sept. 18, 2003, Vol. 39 No. 19	
	2	JANET L. PAN, JOSEPH E.MCMANIS, THOMAS OSADCHY, LOUISE GROBER, JERRY M. WOODALL and PETER J. KINDLMANN, Gallium arsenide deep-leveloptical emitter for fibre optics, Nature Materials, June 2003, pp. 375-378, © 2003 Nature Publishing Group	
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	4	JANET L. PAN, Analytical method for finding the general optical properties of semiconductor deep centers, Journal of Applied Physics, Nov. 15, 2002, pp. 5991-6004, Volume 92, Number 10, © 2002 American Institute of Physics	
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	6	S. FUKUSHIMA, K. MUKAI, N. OTSUKA, X-ray diffraction analysis of LT-GaA's multilayer structures, Journal of Crystal Growth, 2002, pp. 1-5, © 2002 Published by Elsevier Science B.V.	
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	11	PETER C. SERCEL, AL. L. EFROS and M. ROSEN, Intrinsic Gap States in Semiconductor Nanocrystals, Physical Review Letters, Sept. 20, 1999, pp. 2394-2397, Volumn 83, Number 12, © 1999 The American Physical Society	
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